

1.1 Scope.

This specification covers the detail requirements of CMOS monolithic analog multiplexers ADG528A and ADG529A with 8 channels and dual 4 channels, respectively. These multiplexers also feature high switching speeds, low R_{ON} and on-chip latches to facilitate microprocessor interfacing. Break-Before-Make switching is guaranteed.

1.2 Part Number.

The complete part number per Table 1 of this specification is as follows:

Device	Part Number ¹
-1	ADG528AT(X)/883B
-2	ADG529AT(X)/883B

NOTE

¹To complete the part number substitute the package identifier as shown in paragraph 1.2.3.

1.2.3 Case Outline.

See Appendix 1 of General Specification ADI-M-1000: package outline:

(X)	Package	Description
Q	Q-18	18-Pin Cerdip
E	E-20A	20-Terminal LCC

1.3 Absolute Maximum Ratings. ($T_A = +25^\circ\text{C}$)

V+ to V-	44 V
V+ to GND	25 V
V- to GND	-25 V
Analog Inputs	
Voltage at S, D	V- to V+
Continuous Current, S or D	30 mA
Pulsed Current S or D	
1 ms Duration, 10% Duty Cycle	70 mA
Digital Inputs	
Voltages at IN	V- -4 V to V+ +4 V or 20 mA, Whichever Occurs First
Power Dissipation (Package)	
Up to +75°C	470 mW/°C
Derates above +75°C by	6 mW/°C
Operating Temperature	-55°C to +125°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (Soldering 10 sec)	+300°C
Junction Temperature (T_J)	+175°C

1.5 Thermal Characteristics.

Thermal Resistance $\theta_{JC} = 35^\circ\text{C/W}$ for Q-18 and E-20A
 $\theta_{JA} = 120^\circ\text{C/W}$ for Q-18 and E-20A

ADG528A/ADG529A — SPECIFICATIONS

Table 1.

Test	Symbol	Device	Design Limit $T_{min}-T_{max}$	Sub Group 1	Sub Group 2, 3	Test Conditions ¹ /Comments	Units
Switch ON Resistance	R_{DS}	-1, 2	400	300	400	$V_S = +10\text{ V}$; $V_S = -10\text{ V}$; $I_{DS} = 1\text{ mA}$; Test Circuit 1	Ω max
		-1, 2	600	450	600	$V_+ = +10.8\text{ V}$; $V_- = -10.8\text{ V}$; Test Circuit 1	Ω max
Source OFF Leakage Current	I_S (OFF)	-1, 2	50	1	50	$V_+ = +16.5\text{ V}$; $V_- = -16.5\text{ V}$; Test Circuit 2	$\pm\text{nA}$ max
Drain OFF Leakage Current	I_D (OFF)	-1	200	1	200	$V_D = V_S = \pm 10\text{ V}$; $V_+ = +16.5\text{ V}$; $V_- = -16.5\text{ V}$; Test Circuit 3	$\pm\text{nA}$ max
		-2	100	1	100		
Channel ON Leakage Current	I_D (ON)	-1	200	1	200	$V_D = V_S = \pm 10\text{ V}$; $V_+ = +16.5\text{ V}$; $V_- = -16.5\text{ V}$; Test Circuit 4	$\pm\text{nA}$ max
		-2	100	1	100		
Differential OFF Output Leakage	I_{DIFF}	-2	25		25	$V_1 = \pm 10\text{ V}$; $V_2 = \pm 10\text{ V}$; Test Circuit 5	$\pm\text{nA}$ max
Digital Input High Voltage	V_{INH}	-1, 2	2.4	2.4	2.4		V min
Digital Input Low Voltage	V_{INL}	-1, 2	0.8	0.8	0.8		V max
High Level Input Current	I_{INH}	-1, 2	1	1	1	$V_+ = +16.5\text{ V}$; $V_- = -16.5\text{ V}$; $V_{IN} = +16.5\text{ V}$	$\pm\mu\text{A}$ max
Low Level Input Current	I_{INL}	-1, 2	1	1	1	$V_+ = +16.5\text{ V}$; $V_- = -16.5\text{ V}$; $V_{IN} = 0\text{ V}$	$\pm\mu\text{A}$ max
Supply Current	$+I_{OC}$	-1, 2	1.5	1.5	1.5	$V_+ = +16.5\text{ V}$; $V_- = -16.5\text{ V}$; $V_{INH} = 2.4\text{ V}$; $V_{INL} = 0.8\text{ V}$	mA max
	$-I_{OC}$	-1, 2	0.2	0.2	0.2		
Subgroup 9, 10, 11 $t_{TRANSITION}$	t_{TRANS}	-1, 2	400			$V_1 = \pm 10\text{ V}$, $V_2 = \pm 10\text{ V}$; Test Circuit 6	ns max
Subgroup 9, 10, 11 t_{ON} (ENABLE, $\overline{\text{WRITE}}$) t_{OFF} (ENABLE, $\overline{\text{RESET}}$)	t_{ON} (EN, $\overline{\text{WR}}$)	-1, 2	400			Test Circuit 7a, 7b, 7c	ns max
	t_{OFF} (EN, $\overline{\text{RS}}$)	-1, 2	400				
Subgroup 12 Off Isolation	V_{ISO}	-1, 2	50			$R_L = 1\text{ k}\Omega$; $C_L = 12\text{ pF}$; Test Circuit 8 $V_{IN} = 10\text{ V pk-pk}$, $f = 100\text{ kHz}$; $T_A = +25^\circ\text{C}$	dB min
Subgroup 13 Crosstalk between Channels	V_{CT}	-1, 2	60			$V_S = 20\text{ V pk-pk}$; $R_L = 1\text{ k}\Omega$; $C_L = 12\text{ pF}$; $T_A = +25^\circ\text{C}$; Test Circuit 9	dB min
Subgroup 14 Charge Injection	Q_{INJ}	-1, 2	50			Test Circuit 10	pC max
Digital Input Capacitance	C_{IN}	-1, 2	20				pF max
Source Capacitance, OFF	C_S (OFF)	-1, 2	20				pF max
Drain Capacitance, OFF	C_D (OFF)	-1	100				pF max
		-2	50				pF max

NOTE: DUAL SUPPLY OPERATION — $\pm 15\text{ V}$

¹Unless otherwise noted $V_+ = +15\text{ V}$; $V_- = -15\text{ V}$.

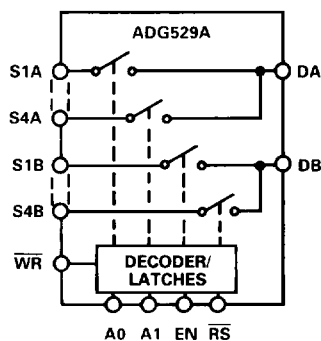
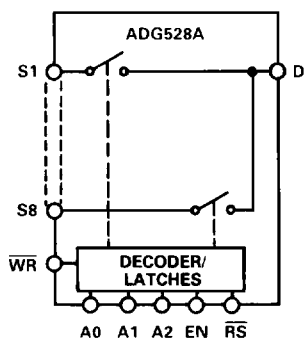
Table 2.

Test	Symbol	Device	Design Limit $T_{min}-T_{max}$	Sub Group 1	Sub Group 2, 3	Test Conditions ¹ /Comments	Units
Switch ON Resistance	R_{DS}	-1, 2	1000	700	1000	$V_D = +10\text{ V}$; $V_S = 0\text{ V}$; $I_{DS} = 0.5\text{ mA}$ $V_+ = +10.8\text{ V}$; $V_- = 0\text{ V}$; Test Circuit 1	Ω max
Source OFF Leakage Current	I_S (OFF)	-1, 2	50	1	50	$V_+ = +16.5\text{ V}$; $V_- = 0\text{ V}$; Test Circuit 2	$\pm\text{nA}$ max
Drain OFF Leakage Current	I_D (OFF)	-1	200	1	200	$V_+ = +16.5\text{ V}$; $V_- = 0\text{ V}$	$\pm\text{nA}$ max
		-2	100	1	100	$V_1 = +10\text{ V}/0\text{ V}$; $V_2 = 0\text{ V}/+10\text{ V}$; Test Circuit 3	
Channel ON Leakage Current	I_D (ON)	-1	200	1	200	$V_+ = +16.5\text{ V}$; $V_- = 0\text{ V}$; $V_1 = +10\text{ V}/0\text{ V}$; $V_2 = 0\text{ V}/+10\text{ V}$	$\pm\text{nA}$ max
		-2	100	1	100	Test Circuit 4	
Differential OFF Output Leakage	I_{DIFF}	-2	25		25	$V_+ = +16.5\text{ V}$; $V_- = 0\text{ V}$ $V_1 = +10\text{ V}/0\text{ V}$; $V_2 = 0\text{ V}/+10\text{ V}$ Test Circuit 5	$\pm\text{nA}$ max
Digital Input High Voltage	V_{INH}	-1, 2	2.4	2.4	2.4		V min
Digital Input Low Voltage	V_{INL}	-1, 2	0.8	0.8	0.8		V max
High Level Input Current	I_{INH}	-1, 2	1	1	1	$V_+ = +16.5\text{ V}$; $V_- = 0\text{ V}$; $V_{IN} = +16.5\text{ V}$	$\pm\mu\text{A}$ max
Low Level Input Current	I_{INL}	-1, 2	1	1	1	$V_+ = +16.5\text{ V}$; $V_- = 0\text{ V}$; $V_{IN} = 0\text{ V}$	$\pm\mu\text{A}$ max
Supply Current	$+I_{CC}$	-1, 2	1.5	1.5	1.5	$V_+ = +16.5\text{ V}$; $V_- = 0\text{ V}$; $V_{INH} = 2.4\text{ V}$; $V_{INL} = 0.8\text{ V}$	mA max
Subgroup 9, 10, 11 $t_{TRANSITION}$	t_{TRANS}	-1, 2	600			$V_1 = 10\text{ V}/0\text{ V}$; $V_2 = 0\text{ V}/10\text{ V}$; Test Circuit 6	ns max
Subgroup 9, 10, 11 t_{ON} (ENABLE, $\overline{\text{WRITE}}$)	t_{ON} (EN, $\overline{\text{WR}}$)	-1, 2	600			Test Circuit 7a, 7b, 7c	ns max
t_{OFF} (ENABLE, $\overline{\text{RESET}}$)	t_{OFF} (EN, $\overline{\text{RS}}$)	-1, 2	600				
Subgroup 12 Off Isolation	V_{ISO}	-1, 2	50				dB min
Subgroup 13 Crosstalk between Channels	V_{CT}	-1, 2	60				dB min
Subgroup 14 Charge Injection	Q_{INJ}	-1, 2	50				pC max
Digital Input Capacitance	C_{IN}	-1, 2	20				pF max
Source Capacitance, OFF	C_S (OFF)	-1, 2	20				pF max
Drain Capacitance, OFF	C_D (OFF)	-1	100				pF max
		-2	50				pF max

NOTE: SINGLE SUPPLY OPERATION - +15 V
¹Unless otherwise noted $V_+ = +15\text{ V}$; $V_- = 0\text{ V}$.

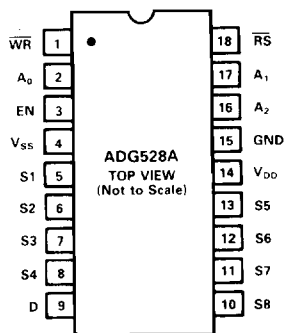
ADG528A/ADG529A

3.2.1 Functional Block Diagram and Terminal Assignments.

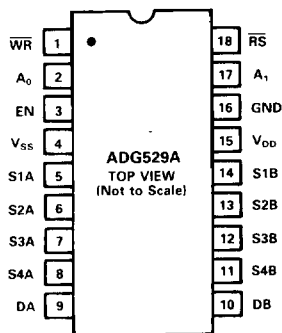


Pin Assignments

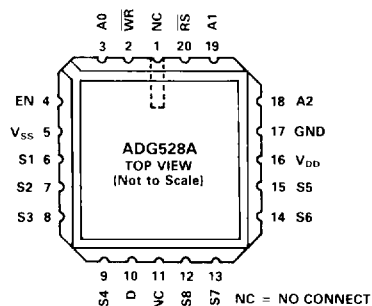
DIP Package



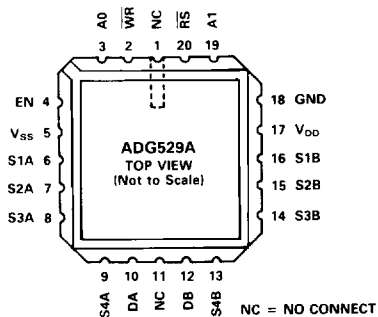
DIP Package



LCCC



LCCC



MIL-STD-883 Test Requirements	Subgroups (See Table 1)
Interim Electrical Parameters (Pre-Burn-In) Method 5004	1
Final Electrical Parameters, Method 5004	1*, 2, 3, 9
Group A Electrical Parameters, Method 5005	1, 2, 3, 9, 10**, 11**
Group C End Point Electrical Parameters, Method 5005	1

NOTES

*Indicates PDA applies to Subgroup 1.

**Subgroups 10 & 11, if not tested, shall be guaranteed to the limits in the data sheet.

TRUTH TABLES

Table 3. ADG528A Truth Table

A2	A1	A0	EN	$\overline{WR}$	$\overline{RS}$	ON SWITCH PAIR
X	X	X	X	$\overline{1}$	1	Retains Previous Switch Condition
X	X	X	X	X	0	NONE (Address and Enable Latches Cleared)
X	X	X	0	0	1	NONE
0	0	0	1	0	1	1
0	0	1	1	0	1	2
0	1	0	1	0	1	3
0	1	1	1	0	1	4
1	0	0	1	0	1	5
1	0	1	1	0	1	6
1	1	0	1	0	1	7
1	1	1	1	0	1	8

X = Don't Care

Table 4. ADG529A Truth Table

A1	A0	EN	$\overline{WR}$	$\overline{RS}$	ON SWITCH PAIR
X	X	X	$\overline{1}$	1	Retains Previous Switch Condition
X	X	X	X	0	NONE (Address and Enable Latches Cleared)
X	X	0	0	1	NONE
0	0	1	0	1	1
0	1	1	0	1	2
1	0	1	0	1	3
1	1	1	0	1	4

X = Don't Care

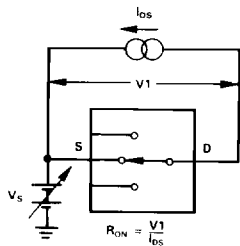
3.2.4 Microcircuit Technology Group.

This microcircuit is covered by technology group (82).

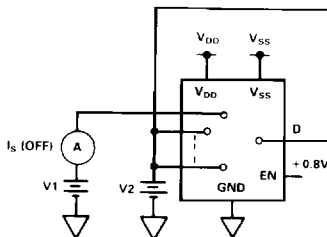
ADG528A/ADG529A

4.2.1 Life Test/Burn-In Circuit.

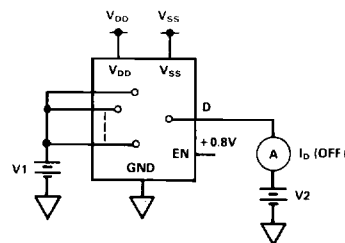
Steady state life test is per MIL-STD-883 Method 1005. Burn-in is per MIL-STD-883 Method 1015 test condition (B).



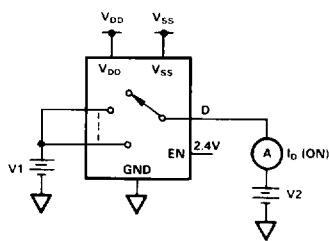
Test Circuit 1
 R_{ON}



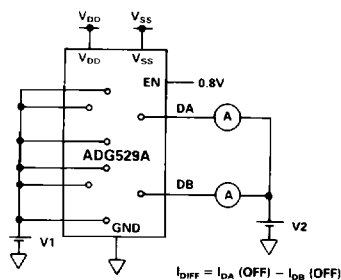
Test Circuit 2
 I_S (OFF)



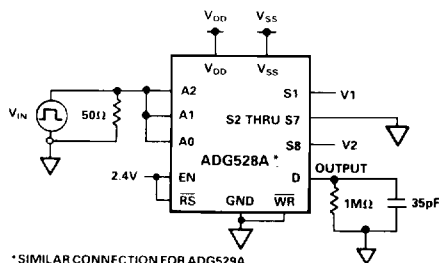
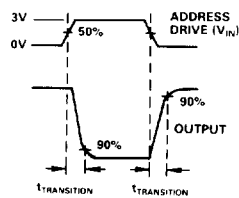
Test Circuit 3
 I_D (OFF)



Test Circuit 4
 I_D (ON)

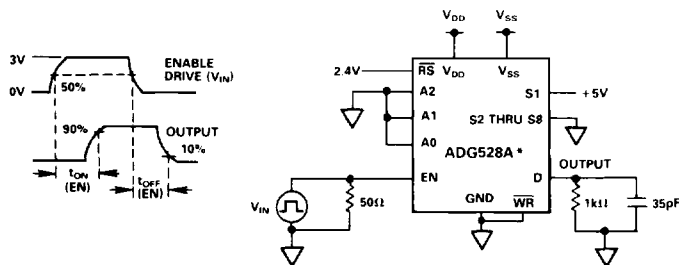


Test Circuit 5
 I_{DIFF}



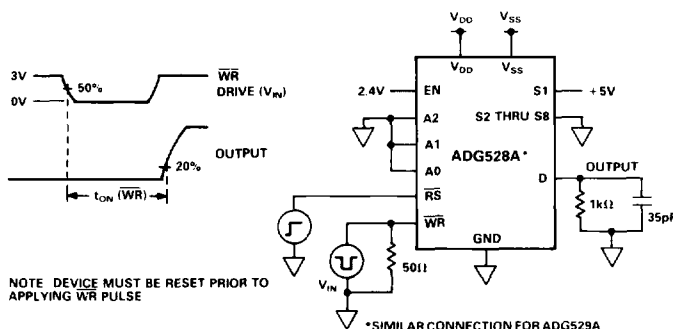
* SIMILAR CONNECTION FOR ADG529A

Test Circuit 6
Switching Time of Multiplexer, $t_{TRANSITION}$



*SIMILAR CONNECTION FOR ADG529A

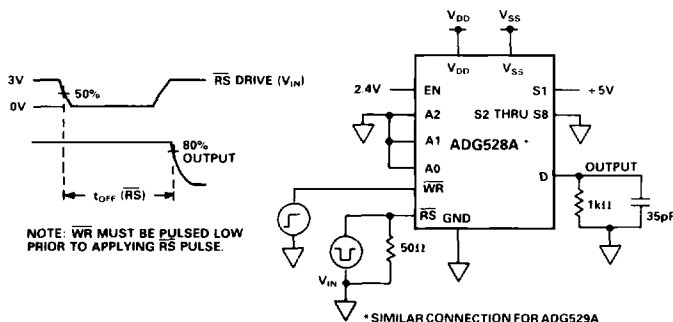
Test Circuit 7a
Enable Delay, $t_{ON}(EN)$, $t_{OFF}(EN)$



NOTE: DEVICE MUST BE RESET PRIOR TO APPLYING WR PULSE

*SIMILAR CONNECTION FOR ADG529A

Test Circuit 7b
Write Turn-On Time, $t_{ON}(\overline{WR})$

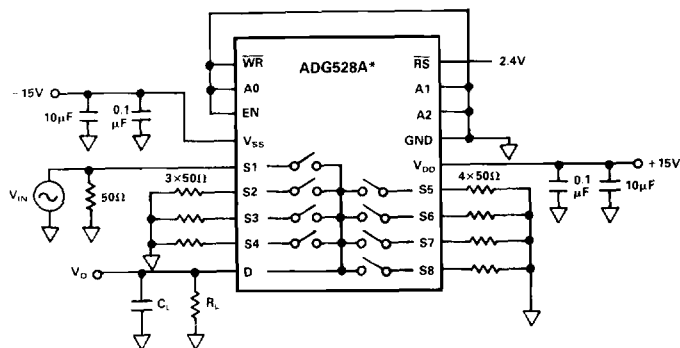


NOTE: $\overline{WR}$ MUST BE PULSED LOW PRIOR TO APPLYING RS PULSE.

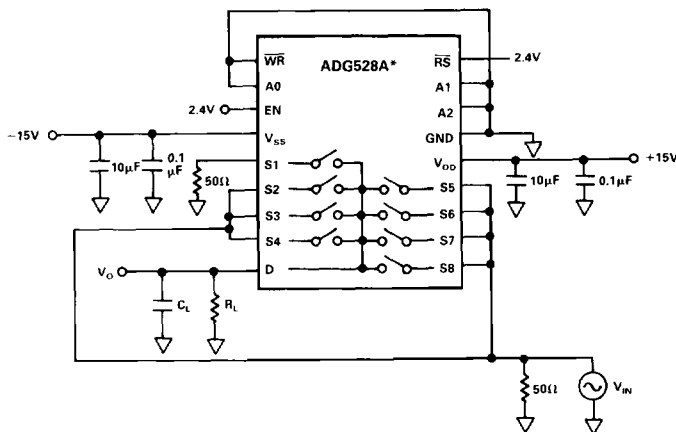
*SIMILAR CONNECTION FOR ADG529A

Test Circuit 7c
Reset Turn-Off Time, $t_{OFF}(\overline{RS})$

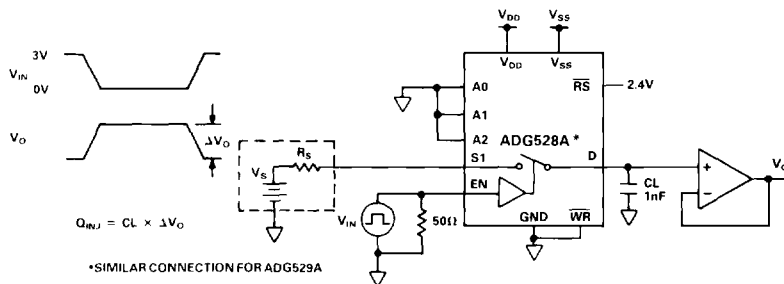
ADG528A/ADG529A



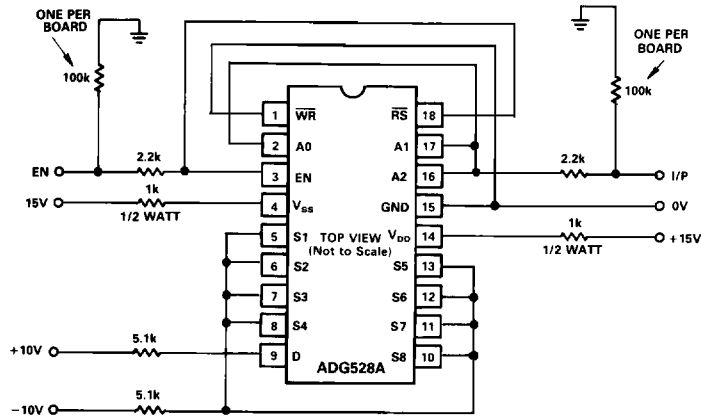
Test Circuit 8
OFF Isolation



Test Circuit 9
Crosstalk Between Channels

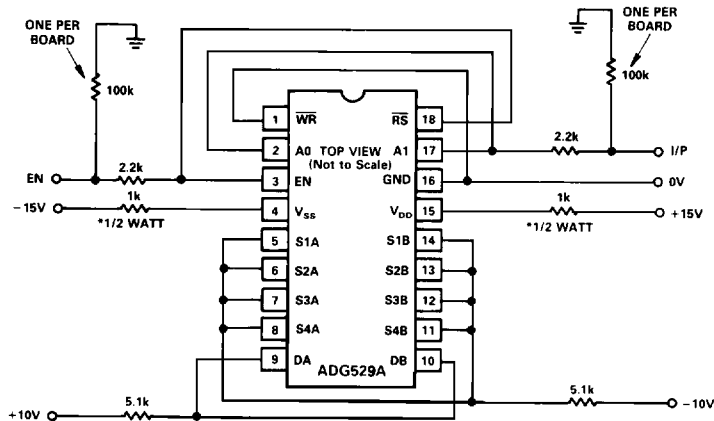


Test Circuit 10
Charge Injection



NOTES
 I/P = +15V; WR = GND; EN = 0V; RS = 0V
 MAX CURRENT RATINGS
 MAX I_{DD} = 2mA NOT THE ABSOLUTE MAX RATINGS
 MAX I_{SS} = 2mA
 MAX CONTINUOUS CURRENT S OR D = 20mA
 N.B. NOTE POWER RATINGS OF 1k RESISTORS

ADG528A Static Burn-In Board



NOTES
 I/P = +15V; WR = GND; EN = 0V; RS = 0V
 MAX CURRENT RATINGS
 MAX I_{DD} = 2mA NOT THE ABSOLUTE MAX RATINGS
 MAX I_{SS} = 2mA
 *N.B. NOTE POWER RATING OF 1k RESISTORS
 MAX CONTINUOUS CURRENT S OR D = 20mA

ADG529A Static Burn-In Board